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LIST OF	KEFE	RENGES CITED BY AF	PLICANT	Yasushi MATSUTAKA						
				FILING DATE			GROUP 2687			
				September 17, 2004			3081			
U.S. PATENT DOCUMENTS										
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME CLASS		CLASS	SUB CLASS			
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FOREIGN PATENT DOCUMENTS										
		DOCUMENT NUMBER	DATE	COUNTRY			TRANSLATION YES NO		- 1	
PHD	AO	2000-032116	01/28/00	JP (with English abstract)		NO		NO		
PAD	AP	2001-111658	04/20/01	JP (with English abstract)					NO	
PHD	AQ	2002-125012	04/26/02	JP (with English abstract & equivalent of US 2002/0045466) JP (with English abstract & partial English					NO	
PHD	AR	2000-295324	10/20/00	translation)				NO		
PHD	AS	2000-278402	10/06/00	JP (with English abstract & partial English translation)					NO	
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)										
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*Examiner; In conformance	*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.									